

Notice of References Cited

Application/Control No.

10/595,434

Applicant(s)/Patent Under
Reexamination
KARG ET AL.

Examiner

JOEL G. HORNING

Art Unit

1792

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U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-2002/0063212	05-2002	Mirkin et al.	250/306
B	US-			
C	US-			
D	US-			
E	US-			
F	US-			
G	US-			
H	US-			
I	US-			
J	US-			
K	US-			
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FOREIGN PATENT DOCUMENTS

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N					
O					
P					
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R					
S					
T					

NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
U	Asahino et al (Physical Review Letters, Volume 86(2001), Number 19, pp 4334-4337).
V	Takahashi et al (Ultramicroscopy, Volume 82 (2000), pp63-68).
W	
X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))
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